

# Controllable Ozone Oxidation on N-type MoS<sub>2</sub> to Make Ambipolar or P-type MoO<sub>x</sub>/MoS<sub>2</sub> Transistors

Bang-Jia Jhang, Jian-Jhong Lai, Po-Sheng Wang, Bing-Shiuan Shie, **Wen-Bin Jian**  
*Department of Electrophysics, National Chiao Tung University, Hsinchu, Taiwan*

The discovery of single layer graphene helps to establish experimental techniques to process layered materials. Recently, semiconducting layered materials such as MoS<sub>2</sub> and WSe<sub>2</sub> attract much attention because these materials show prominent potential to replace Si or Si/Ge bodies as channel materials. As the body width of fin field-effect transistors (FETs) is continually downsized to several nanometer, the three-dimensional nature of the Si lattice structure hinder further thinner manufacture due to dangling bonds at surface. In contrast, the semiconducting layered materials are natively saturated without dangling bonds thus paving the way to the atomic thin FETs. The MoS<sub>2</sub> single layer usually shows n-type features, limiting its application in FETs. Here, we show controllable oxidation to convert MoS<sub>2</sub> with thickness of few-tens of nanometers to either ambipolar or p-type FETs.

The MoS<sub>2</sub> flakes are heated at 150°C or 270°C under ozone exposure for several hours. The surface of oxidized MoS<sub>2</sub> was examined by scanning tunneling microscope and scanning tunneling spectroscopy. Further, we made FET devices on MoS<sub>2</sub> flakes with a thickness of few-tens of nanometers. Before ozone oxidation, the FET devices presented n-type features that are consistent with others' reports. After the MoS<sub>2</sub> FETs were oxidized, the devices showed Schottky contact properties which were inspected at different source-drain bias voltages and different back-gating voltages. The MoS<sub>2</sub> FETs after minor oxidation treatments showed an ambipolar feature and electron transport in channels was studied. On the other hand, the MoS<sub>2</sub> FETs under stronger oxidation treatments presented p-type FET behaviors. The electron transport and transfer characteristics in the p-type FETs were explored. From experimental data, we propose a band diagram to explain the oxidation, the formation of MoO<sub>x</sub>/MoS<sub>2</sub> heterostructure, and the variation of electron transport manners.